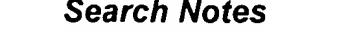


<b>Search Notes</b> 	<b>Application/Control No.</b> 09/901,013	<b>Applicant(s)/Patent under Reexamination</b> CHU, WEI-SING
	<b>Examiner</b> Christopher L. Chin	<b>Art Unit</b> 1641

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner